

RCE # 2800
 13/RCE
 P. Walker
 2-27-03

O I P E
 FEB 19 2003
 RECEIVED

**REQUEST
FOR
CONTINUED EXAMINATION (RCE)
TRANSMITTAL**

Subsection (b) of 35 U.S.C. § 132, effective on May 29, 2000, provides for continued examination of an utility or plant application filed on or after June 8, 1995.
See the American Inventors Protection Act of 1999 (AIPA).

Application Number	09/576,442
Filing Date	May 22, 2000
First Named Inventor	David JACKSON et al
Group Art Unit	2863
Examiner Name	S. Cherry
Attorney Docket Number	10473-678

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application

NOTE: 37 C.F.R. § is effective on May 29, 2000. If the above-identified application was filed prior to May 29, 2000, applicant may wish to consider filing a continued prosecution application (CPA) under 37 C.F.R. § 1.53 (d) (PTO/SB/29) instead of a RCE to be eligible for the patent term adjustment provisions of the AIPA. See Changes to Application Examination and Provisional Application Practice, Interim Rule, 65 Fed. Reg. 14865 (Mar. 20, 2000), 1233 Off. Gaz. Pat. Office 47 (Apr. 11, 2000), which established RCE practice.

1. **Submission required under 37 C.F.R. § 1.114**

a. ☐ Previously submitted

i. ☐ Consider the amendment(s)/reply under 37 C.F.R. § 1.116 previously filed on _____
(Any unentered amendment(s) referred to above will be entered).

ii. ☐ Consider the arguments in the Appeal Brief or Reply Brief previously filed on _____

iii. ☐ Other _____

b. ☒ Enclosed

i. ☒ Amendment/Reply

ii. ☐ Affidavit(s)/Declaration(s)

iii. ☐ Information Disclosure Statement (IDS)

iv. ☐ Other _____

2. **Miscellaneous**

a. ☐ Suspension of action of the above-identified application is requested under 37 C.F.R. § 1.1.03(c) for a period of _____ months. (Period of suspension shall not exceed 3 months; Fee under 37 C.F.R. § 1.17(i) required)

b. ☐ Other _____

3. **Fees** The RCE fee under 37 C.F.R. § 1.17(e) is required by 37 C.F.R. § 1.114 when the RCE is filed.

a. ☐ The Director is hereby authorized to charge the following fees, or credit any overpayments, to Deposit Account No. 500417.

i. ☒ RCE fee required under 37 C.F.R. § 1.17(e) **\$750.00**

ii. ☐ Extension of time fee (37 C.F.R. §§ 1.136 and 1.17)

iii. ☒ Other: Additional Claims Fee **\$342.00** 02/21/2003 AWONDAF1 00000150 500417 09576442

b. ☐ Check in the amount of \$_____ enclosed

01 FC:1801 750.00 CH

02 FC:1201 252.00 CH

c. ☐ Payment by credit card (Form PTO-2038 enclosed)

03 FC:1202 00.00 CH

RECEIVED
 FEB 24 2003
 TECHNOLOGY CENTER 2800

SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT REQUIRED

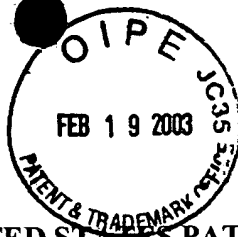
Name (Print/Type)	Wei-Chen Chen	Registration No. (Attorney/Agent)	Recognition under 37 CFR 10.9(b)
Signature			
	February 19, 2003		

CERTIFICATE OF MAILING OR TRANSMISSION

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to Commissioner For Parents, Box RCE, Washington, D.C. 20231, or facsimile transmitted to the U.S. Patent and Trademark Office on:

Name(Print/Type)	
Signature	Date

Docket No.: 10473-678



14/C
P. W. N.
22783
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

David A. JACKSON, et al.

Serial No.: 09/576,442

Filed: May 22, 2000

Group Art Unit: 2863

Examiner: S. Cherry

For: SELF-CALIBRATING, MULTI-CAMERA MACHINE VISION MEASURING SYSTEM

RECEIVED
FEB 24 2003
TECHNOLOGY CENTER 2800

AMENDMENT

Assistant Commissioner for Patents
Washington, DC 20231

Sir:

The following amendment and remarks are submitted in response to the Official Action mailed November 15, 2002. A mark-up version showing changes made is also attached hereto.

IN THE CLAIMS

Please amend claims 21, 22, 34 and 38 as follows.

C1 Sub
Cont'd

21. (Twice Amended) A method for calibrating a machine measuring system that has a first measuring device and a second measuring device, the method comprising the steps of:

mounting a first calibration target in a predetermined relationship to the first measuring device of the machine measuring system, wherein the first measuring device is configured to measure a relative position between the first measuring device and a first object;

mounting a third measuring device in a predetermined relationship to the second measuring device of the machine measuring system, wherein the second measuring device is